

Team #:	P18262	Team Name:	EVT BMS
Date:	10/31/17	Document Owner:	Ben Stewart
Revision #:	1		

Subsystem/ Function/ Feature Name:	MCU Communication Testing
Date of Test:	
Performed By:	BPS
Tested By:	BPS

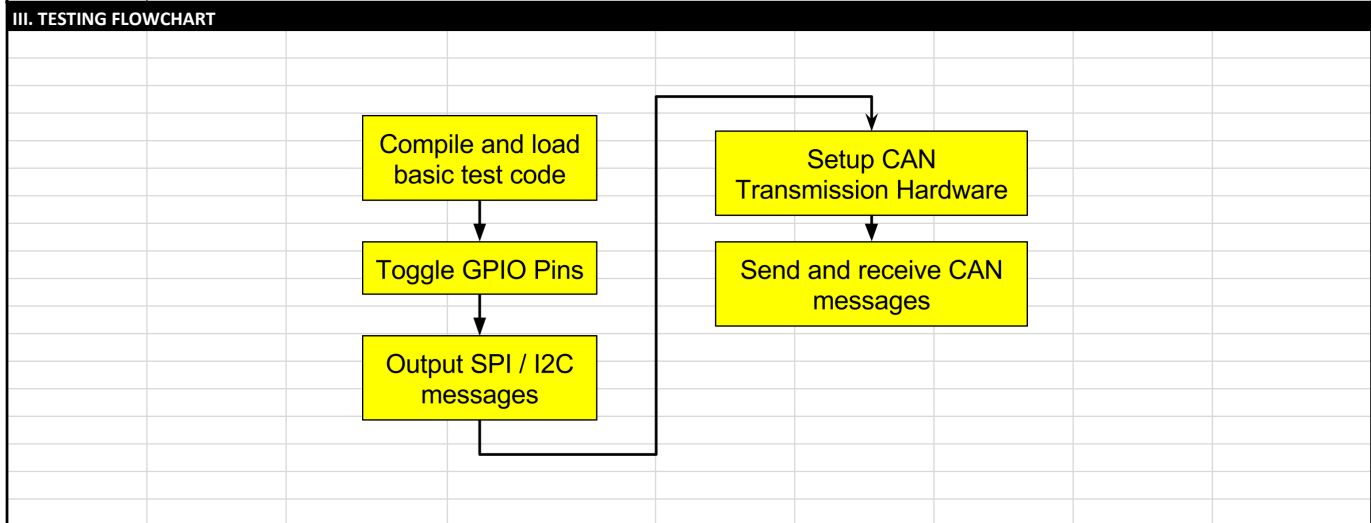
Concluded Condition of meeting Engineering Specification:

O- Meets Marginal Value

I. TESTING SPECIFICATION								
Specification Number	Importance	Source	Function	Specification (Metric)	Unit of Measure	Marginal Value	Ideal Value	Comments/Status
S1	1	CR1	Compliance / Performance	Pass / Fail			Pass	Feasibility of F3 Series
S2, S3, S4, S5	3	CR1, CR7	Communication / Safety	Pass / Fail			Pass	CAN
S6	3	CR1, CR9	Communication	Pass / Fail			Pass	SPI / I2C

II. EQUIPMENT REQUIRED	
Specification Number	Equipment or Instrumentation required
S1	STMF3 Microcontroller Dev Board
S2, S3, S4, S5	Two STMF3 Microcontroller Dev Boards, CAN Transceivers
S6	STMF3 Microcontroller Dev Board

III. DATA COLLECTION STRATEGY	
Specification Number	Data acquisition strategy
S1	Run basic test code on development boards.
S2, S3, S4, S5	Sucesfully transmit CAN messages between development boards
S6	Sucesfully output SPI and I2C master messages



IV. RAW DATA ACQUISITION	
Raw data files have been compressed and uploaded to edge.	
Size of data too large to fit here.	
http://edge.rit.edu/edge/P18262/public/	

V. RESULTS	
Specification Number	Test Results
S1	PASS
S2, S3, S4, S5	PASS
S6	PASS

VI. CONCLUSION	
STMF3 has been proven sufficient for the requirements of this project.	